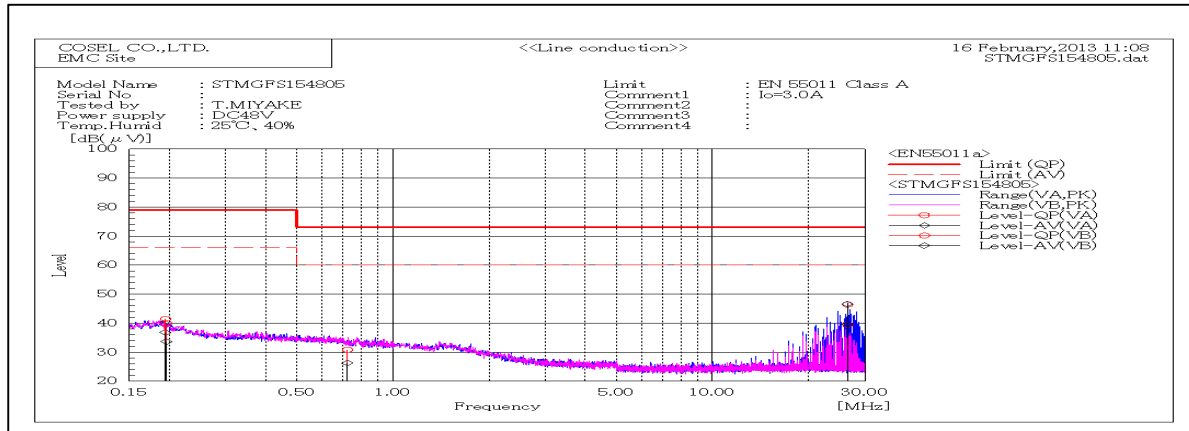
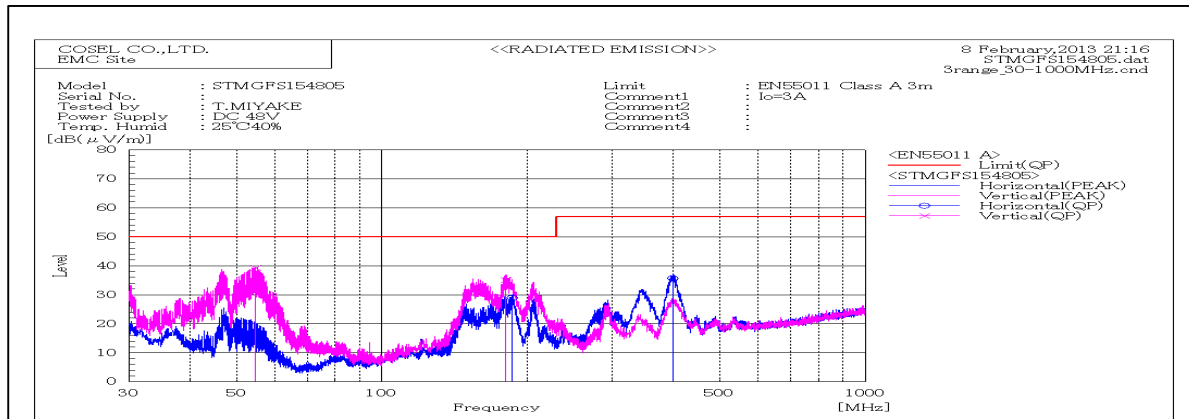


DATA SHEET		Date	18-Feb-13
Model	STMGFS154805	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



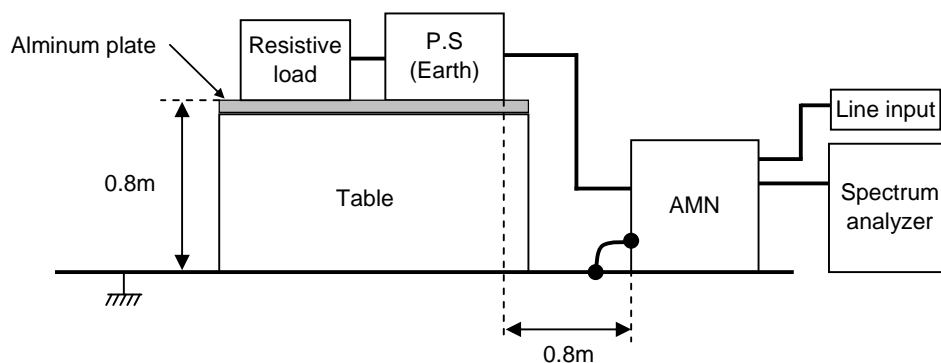
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.19472		VA	21.2	16.6	20.2	41.4	36.8	79	66	37.6	29.2	Pass	
0.1962		VB	19.9	13.6	20.1	40	33.7	79	66	39	32.3	Pass	
0.72213		VB	10.7	6.1	20.1	30.8	26.2	73	60	42.2	33.8	Pass	
26.4482		VB	18.4	18.5	21.1	39.5	39.6	73	60	33.5	20.4	Pass	
26.4495		VA	25.4	25.6	21	46.4	46.6	73	60	26.6	13.4	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
54.713	V	Stable	63.3		-24	39.3		50	10.7	Pass	102	181	
180.648	V	Stable	51.1		-16	35.1		50	14.9	Pass	101	180	
186.186	H	Stable	51.3		-22.3	29		50	21	Pass	148	51	
400.072	H	Stable	47.3		-11.6	35.7		57	21.3	Pass	103	253	

DATA SHEET		Date	18-Feb-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

1. Line conduction



2. Radiated emission

